

**PCN# 20140715000**  
**Qualification of Fluorine Free ILD on CMOS9T Technology**  
**Change Notification / Sample Request**

**Date:** 7/15/2014  
**To:** Newark/Farnell PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager ([PCN\\_ww\\_admin\\_team@list.ti.com](mailto:PCN_ww_admin_team@list.ti.com)).

Sincerely,

PCN Team  
SC Business Services  
Phone: +1(214) 480-6037  
Fax: +1(214) 480-6659

**20140715000**  
**Attachment: 1**

**Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

<b>DEVICE</b>	<b>CUSTOMER PART NUMBER</b>
ADS1293CISQE/NOPB	null
LDC1000NHRT	null

Technical details of this Product Change follow on the next page(s).

<b>PCN Number:</b>	20140715000			<b>PCN Date:</b>	07/15/2014
<b>Title:</b>	Qualification of Fluorine Free ILD on CMOS9T 5V technology.				
<b>Customer Contact:</b>	<a href="#">PCN Manager</a>	<b>Phone:</b>	+1(214)480-6037	<b>Dept:</b>	Quality Services
<b>*Proposed 1<sup>st</sup> Ship Date:</b>	10/15/2014	<b>Estimated Sample Availability:</b>	Date Provided at Sample request		
<b>Change Type:</b>					
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Assembly Materials
<input type="checkbox"/>	Design	<input type="checkbox"/>	Electrical Specification	<input type="checkbox"/>	Mechanical Specification
<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process
<input type="checkbox"/>	Wafer Bump Site	<input type="checkbox"/>	Wafer Bump Material	<input type="checkbox"/>	Wafer Bump Process
<input type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Wafer Fab Materials	<input checked="" type="checkbox"/>	Wafer Fab Process
		<input type="checkbox"/>	Part number change		
<b>PCN Details</b>					
<b>Description of Change:</b>					
This change notification is to announce the qualification of Fluorine Free ILD dielectric composition on the CMOS9T 5V technology.					
<b>Current</b>					
Chip Site	Fab Process	Wafer Diameter	Fluorine ILD Composition		
MAINEFAB	CMOS9T 5V	200mm	HDP = 4.5%, FSG=6.0%		
<b>New</b>					
<b>Chip Site</b>	<b>Fab Process</b>	<b>Wafer Diameter</b>	<b>Fluorine ILD Composition</b>		
<b>MAINEFAB</b>	<b>CMOS9T 5V</b>	<b>200mm</b>	<b>0%</b>		
<b>Reason for Change:</b>					
Continuity of supply.					
<b>Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):</b>					
None					
<b>Changes to product identification resulting from this PCN:</b>					
None					
<b>Product Affected:</b>					
ADS1293CISQ/NOPB	LDC1000NHRR	LMP90507CISQX/NOPB	LMP91300NHZR		
ADS1293CISQE/NOPB	LDC1000NHRT	LMP91010DGSR	LMP91300NHZT		
ADS1293CISQX/NOPB	LMP90507CISQ/NOPB	LMP91010DGST	LMP91300YZRR		
LDC1000NHRJ	LMP90507CISQE/NOPB	LMP91300NHZJ	LMP91300YZRT		

## Reference Qualification Data: CMOS9T-5V Fluorine Free Process

### Qualification Data: (Approved 4/16/2013)

This qualification has been developed for the validation of this change. The qualification data will validate that the proposed change meets the applicable released technical specifications.

#### Qualification Device: LM3533TME (MSL LEVEL1-260C)

##### Package Construction Details

Wafer Fab Site:	MAINEFAB	Wafer Fab Process:	CMOS9T 5V
Wafer Diameter:	200mm	Metallization:	Al .5%Cu
Passivation:	OXIDE/NITRIDE		

Qualification:  Plan  Test Results

Reliability Test	Conditions	Sample Size / Fail	
		Lot# 1	Lot# 2
High Temp Operating Life	125C (1000 Hrs)	77/0	-
Temp Cycle	-65/150C (500 Cyc)	77/0	77/0

\*\*Preconditioning: MSL1@260C

### Qualification Data: (Approved 4/23/2013)

This qualification has been developed for the validation of this change. The qualification data will validate that the proposed change meets the applicable released technical specifications.

#### Qualification Device: LM8330TME/NOPB (MSL LEVEL1-260C)

##### Package Construction Details

Wafer Fab Site:	MAINEFAB	Wafer Fab Process:	CMOS9T 5V
Wafer Diameter:	200mm	Metallization:	Al .5%Cu
Passivation:	OXIDE/NITRIDE		

Qualification:  Plan  Test Results

Reliability Test	Conditions	Sample Size / Fail	
		Lot# 1	Lot# 2
High Temp Operating Life	150C (500 Hrs)	77/0	-

\*\*Preconditioning: MSL1@260C

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	<a href="mailto:PCNAmericasContact@list.ti.com">PCNAmericasContact@list.ti.com</a>
Europe	<a href="mailto:PCNEuropeContact@list.ti.com">PCNEuropeContact@list.ti.com</a>
Asia Pacific	<a href="mailto:PCNAsiaContact@list.ti.com">PCNAsiaContact@list.ti.com</a>
Japan	<a href="mailto:PCNJapanContact@list.ti.com">PCNJapanContact@list.ti.com</a>